Study of a MAPS Detector Prototype

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MAPS and prototype for MDC Upgrade



- MAPS(Monolithic active pixel sensor) 具有低物质量、高空间分辨率等优
- 法国Strasbourg IPHC
- 应用于STAR vertex detector 及ALICE ITS upgrade 等



- MDC内室升级预研采用MIMOSA28
- Density: 20.7µm pixel pitch, ~0.9Mpixels/chip
- Spatial resolution: a few μm
- Rating capability: ~10⁶Hz/cm²
- Material budget: ~50µm thick
- Radiation tolerance: ~1 MRad, 10¹³ n_{eq}/cm²
- Room temperature operation

R&D target: a MAPS Prototype



- 探测器模型结构
 - 1/10 Coverage of the inner tracker (~ 720cm²→180 chips→180M pixels)
 - φ direction: 2 , 3 and 4 ladders for the 1st, 2nd and 3rd layer respectively
 - Z direction: 2 sets of ladders each layer
 - 10 Mimosa28 chips with dimension of 2cm imes 2cm in each ladder
- Chip \rightarrow ladder \rightarrow sector \rightarrow layer \rightarrow prototype

Ladder Design



Ladder Assembly



- Ladder assembly was operated at a dedicated jigs to ensure the location accuracy of the chips
- 低物质量、高位置精度探测模块
 - Material budget calculation: 0.37% X₀ /ladder, 0.51% X₀ /layer (ladder + supporter)
 - Chip location accuracy by imaging machine: < 10μm



Readout Electronics and DAQ



Readout speed: 30~40MB/s/ladder

Data base

for log files

Event

reconstruction

and package

Data

saving

Ladder Test





- 硬板PCB→柔性PCB
- 单片芯片测试→双片芯片测试 →完整ladder的测试
- Ladder 批量研制→ladder系统放射源测试→ladder系统束流测试

Test Beam in DESY



Test Beam in DESY

- Energy Scan
- Ladder scan
- Threshold scan
- Gap between the neighboring chips
- Material budget test
- Target scattering test
- Cooling air flow







System Setup



Analysis Software Framework



- Hit reconstruction : cluster size, digital signal, no seed
- Alignment: high precision
- Tracking

Cluster Size Analysis



- Charge collection by thermal diffusion
- Charges sharing: one hit can lead to several fired pixels, be benefit to spatial resolution
- Reconstruction algorithm

Alignment Results



Spatial Resolution and Efficiency





Gap between two chips







- D1≈D2 ≈ 340µm
- Average gap between neighboring chips is 340 μm
- Take into account the row sequencer on the chip, chip location accuracy is better than 10µm

Multiple Scattering

- High-energy particles undergo multiple coulomb scattering when passing through the material;
- Kink angle depends on material budget (x/X0);
- The width of the gaussian-like center is well predicted by the Highland formula;

> Highland formula:
$$\theta_0 = \frac{13.6MeV}{\beta cp} Z \sqrt{\frac{x}{X_0}} \left(1 + 0.038 \ln\left(\frac{x}{X_0}\right)\right)$$

 θ_0 = RMS of scattering angle z = charge of incident particle x = material thickness

 X_0 = radiation length



Material budget



Target Test

Goal :Getting the target image according to multiple scattering.

- Target in front of plane 1.
- Target:Ø=4mm.
- Target:thickness=1mm





The target's material is copper and $\frac{x}{X_0}|_{\text{theoretical}}=21.97\% X_0$ $\theta_0=0.00115 \text{ rad}, P = 5 \text{GeV} \longrightarrow \frac{x}{X_0}=20.259\%$

Double-sided ladder



- Single-sided ladder → Double sided ladder (CEPC vertex 预研)
- Dummy ladder \rightarrow functional ladder

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Summary

- The Mass production and performance test of the pixel detector ladders have been finished
- A detector prototype system was set up and tested at T24 beam line in the DESY
- Good performance have been obtained: spatial resolution:
 5 μm, efficiency : 96%, high location accuracy of the chips:
 10μm, low material budget: 0.39% X₀
- Gain the ability and experience on the key technology and method in the construction of silicon pixel detector for the future high energy physics experiment

Thanks for your attention !